FORM PTO 1449 (modified) APPLICATION NO. 03500.005745.36 09/384,326 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE APPLICANT LIST OF REFERENCES CITED BY APPLICA SEISHIRO YOSHIOKA ET AL. (Use several sheets if nec FILING DATE GROUP MAY 12, 2000 2879 **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT FILING DATE IF APPROPRIATE NUMBER DATE NAME SUBCLASS **CLASS** 5,185,554 2/93 Nomura et al. 313 495 4,954,744 9/90 Suzuki et al. 313 336 5,285,129 2/94 Takeda et al. 13 309 5,256,936 10/93 Itoh et al. 313 309 5,559,342 9/96 Tsukamoto et al. 257 10 5,141,460 8/92 Jaskie et al. 313 309 3,611,077 10/71 **Smith** 315 94 3,631,291 12/71 **Favreau** 313 346 3,983,443 9/76 Schade 313 346DC 4,093,562 6/78 **Kishimoto** 313 103CM 4,672,268 6/87 Duenisch et al. 313 346R 4,663,559 5/87 Christensen 313 346R Sheldon et al. 4,721,524 1/88 75 0.5A 9/19/86 2,887,413 5/59 Ekkers et al. 313 341 4,680,500 7/87 Buck 313 346R 3/6/86 3,766,423 10/73 Menelly 313 341 3,581,151 5/71 Boyle et al. 257 10 3,806,372 4/74 Sommer 257 10 3,814,968 6/74 Nathanson et al. 257 10 4,303,930 12/81 Van Gorkom et al. 257 10 4,683,399 7/87 257 Sociof 10 6/81

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FORM PTO 1449 (modified) ATTY DOCKET NO. APPLICATION NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE 03500.005745.36 09/384,326 APPLICANT LIST OF REFERENCES CITED BY APPLICANT(S) SEISHIRO YOSHIOKA ET AL. (Use several sheets if necessary) JAN 2 4 2002 FILING DATE MAY 12, 2000 2879 U.S. PATENT DOCUMENTS TRADEM DATE *EXAMINER DOCUMENT INITIAL FILING DATE NUMBER NAME CLASS SUBCLASS 4,599,076 7/86 Yokono et al. 313 355 3,990,914 11/76 Weinstein et al. 437 3 5,327,050 7/94 Tsukamoto et al. 313 363 5,627,111 5/97 Tsukamoto et al. 438 20 5,559,342 9/96 Tsukamoto et al. 257 10 4/6/95 5,063,327 11/91 Brodie et al. 3/3 6,169,356 Ohnishi et al. 1/01 313 313 3,663,857 5/72 Soellner 3,79 FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER TRANSLATION YES/NO/ OR ABSTRACT DATE COUNTRY CLASS SUBCLASS 0299461A2 1/89 HOIT **EPO ENGLISH** 1/30 64-31332A 2/89 **JAPAN H01J** 029/48 **ABSTRACT** ķ 1-283749 11/89 **JAPAN** H₀1J 031/15 **ABSTRACT** ŧ 1-309242 12/89 **JAPAN** 37,66 HOIJ **ABSTRACT** 0536731A1 4/93 **EPO** HO1J 1/30 **ENGLISH** 0523702A1 1/93 **EPO** H01J 31/12 **ENGLISH** 59-169034 ι 9/84 **JAPAN** HOIT 1/14 **ABSTRACT** 2060991A 5/81 UK 313 346R **ENGLISH** b 61-156265 7/86 **JAPAN** G03G 15/00 **ABSTRACT** OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) "Thin Film Handbook", Committee 131 of Japanese Society for the Promotion of Art and Science (1983) (English-Language translation pages 1-18 "Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-insulator-metal Diodes", H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69 No. 1, 25-32 (1990) Day M **EXAMINER** DATE CONSIDERED 7/9/02

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